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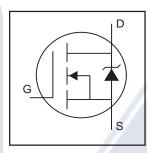
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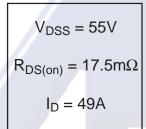
IRFZ44N

HEXFET® Power MOSFET



- Advanced Process Technology
- Ultra Low On-Resistance
- Dynamic dv/dt Rating
- 175°C Operating Temperature
- Fast Switching
- Fully Avalanche Rated





Description

Advanced HEXFET® Power MOSFETs from International Rectifier utilize advanced processing techniques to achieve extremely low on-resistance per silicon area. This benefit, combined with the fast switching speed and ruggedized device design that HEXFET power MOSFETs are well known for, provides the designer with an extremely efficient and reliable device for use in a wide variety of applications.

The TO-220 package is universally preferred for all commercial-industrial applications at power dissipation levels to approximately 50 watts. The low thermal resistance and low package cost of the TO-220 contribute to its wide acceptance throughout the industry.



Absolute Maximum Ratings

	Parameter	Max.	Units
$I_D @ T_C = 25^{\circ}C$	Continuous Drain Current, V _{GS} @ 10V	49	
$I_D @ T_C = 100^{\circ}C$	Continuous Drain Current, V _{GS} @ 10V	35	Α
I _{DM}	Pulsed Drain Current ①	160	- 7
P _D @T _C = 25°C	Power Dissipation	94	W
	Linear Derating Factor	0.63	W/°C
V_{GS}	Gate-to-Source Voltage	± 20	V
I _{AR}	Avalanche Current①	25	Α
E _{AR}	Repetitive Avalanche Energy①	9.4	mJ
dv/dt	Peak Diode Recovery dv/dt ③	5.0	V/ns
T _J	Operating Junction and	-55 to + 175	
T _{STG}	Storage Temperature Range		°C
	Soldering Temperature, for 10 seconds	300 (1.6mm from case)	
	Mounting torque, 6-32 or M3 srew	10 lbf•in (1.1N•m)	

Thermal Resistance

	Parameter	Тур.	Max.	Units
$R_{\theta JC}$	Junction-to-Case		1.5	
R _{θCS}	Case-to-Sink, Flat, Greased Surface	0.50		°C/W
$R_{\theta JA}$	Junction-to-Ambient		62	

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Electrical Characteristics @ T_J = 25°C (unless otherwise specified)

	Parameter	Min.	Тур.	Max.	Units	Conditions
V _{(BR)DSS}	Drain-to-Source Breakdown Voltage	55			V	$V_{GS} = 0V, I_D = 250\mu A$
$\Delta V_{(BR)DSS}/\Delta T_{J}$	Breakdown Voltage Temp. Coefficie	nt	0.058		V/°C	Reference to 25°C, I _D = 1mA
R _{DS(on)}	Static Drain-to-Source On-Resistance	ce		17.5	mΩ	V _{GS} = 10V, I _D = 25A ④
V _{GS(th)}	Gate Threshold Voltage	2.0		4.0	V	$V_{DS} = V_{GS}, I_D = 250 \mu A$
g fs	Forward Transconductance	19			S	V _{DS} = 25V, I _D = 25A ⁽⁴⁾
I _{DSS}	Drain-to-Source Leakage Current			25 250	μA	$V_{DS} = 55V, V_{GS} = 0V$ $V_{DS} = 44V, V_{GS} = 0V, T_{J} = 150^{\circ}C$
	Gate-to-Source Forward Leakage			100	n A	V _{GS} = 20V
I _{GSS}	Gate-to-Source Reverse Leakage			-100	nA	V _{GS} = -20V
Q _g	Total Gate Charge			63		I _D = 25A
Q _{gs}	Gate-to-Source Charge			14	nC	$V_{DS} = 44V$
Q _{gd}	Gate-to-Drain ("Miller") Charge			23		V _{GS} = 10V, See Fig. 6 and 13
t _{d(on)}	Turn-On Delay Time		12		77	$V_{DD} = 28V$
t _r	Rise Time		60	_	ns	I _D = 25A
t _{d(off)}	Turn-Off Delay Time		44	7/	115	$R_G = 12\Omega$
t _f	Fall Time		45	-		V _{GS} = 10V, See Fig. 10 ④
L _D	Internal Drain Inductance		4.5	-	nH	Between lead, 6mm (0.25in.)
L _S	Internal Source Inductance	_	7.5		ПП	from package and center of die contact
C _{iss}	Input Capacitance		1470			V _{GS} = 0V
Coss	Output Capacitance		360	_		$V_{DS} = 25V$
C _{rss}	Reverse Transfer Capacitance		88		pF	f = 1.0MHz, See Fig. 5
E _{AS}	Single Pulse Avalanche Energy ^②		530⑤	150⑥	mJ	I _{AS} = 25A, L = 0.47mH

Source-Drain Ratings and Characteristics

	Parameter	Min.	Тур.	Max.	Units	Conditions
Is	Continuous Source Current			49	/	MOSFET symbol
77 (+	(Body Diode)			49	Α	showing the
I _{SM}	Pulsed Source Current	4. /	~	160	_ ^	integral reverse
	(Body Diode)①			160		p-n junction diode.
V _{SD}	Diode Forward Voltage			1.3	V	$T_J = 25^{\circ}C, I_S = 25A, V_{GS} = 0V $ ④
t _{rr}	Reverse Recovery Time		63	95	ns	$T_J = 25$ °C, $I_F = 25$ A
Q _{rr}	Reverse Recovery Charge		170	260	nC	di/dt = 100A/µs ④
t _{on}	Forward Turn-On Time	Intrinsic turn-on time is negligible (turn-on is dominated by L _S +L _D)				

Notes:

- ① Repetitive rating; pulse width limited by max. junction temperature. (See fig. 11)
- ② Starting $T_J = 25$ °C, L = 0.48mH $R_G = 25\Omega$, $I_{AS} = 25A$. (See Figure 12)
- $\label{eq:loss} \begin{array}{l} \text{ } 3 \text{ } I_{SD} \leq 25\text{A, di/dt} \leq 230\text{A/}\mu\text{s, } V_{DD} \leq V_{(BR)DSS}, \\ T_{J} \leq 175^{\circ}\text{C} \end{array}$
- 4 Pulse width $\leq 400 \mu s$; duty cycle $\leq 2\%$.
- ⑤ This is a typical value at device destruction and represents operation outside rated limits.
- $\mbox{\ensuremath{\ensuremath{\mbox{\ensuremath{\mbox{\ensuremath{\mbox{\ensuremath{\mbox{\ensuremath{\mbox{\ensuremath{\mbox{\ensuremath{\mbox{\ensuremath{\mbox{\ensuremath{\mbox{\ensuremath}\ens$

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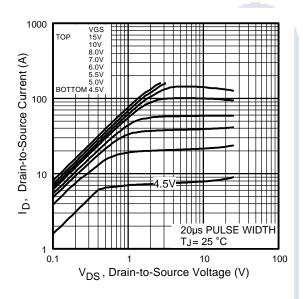


Fig 1. Typical Output Characteristics

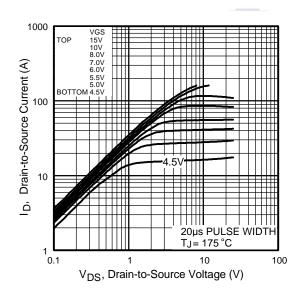


Fig 2. Typical Output Characteristics

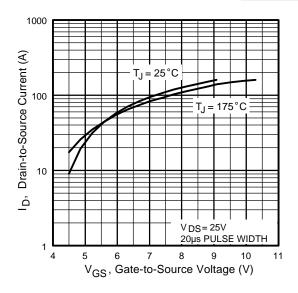


Fig 3. Typical Transfer Characteristics

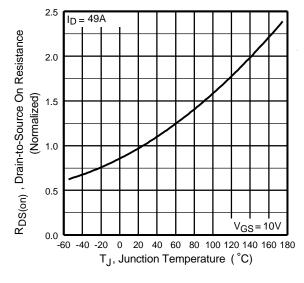


Fig 4. Normalized On-Resistance Vs. Temperature

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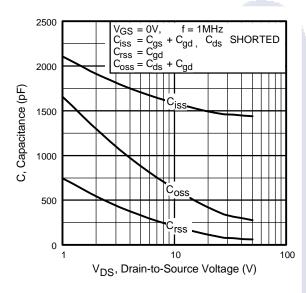


Fig 5. Typical Capacitance Vs. Drain-to-Source Voltage

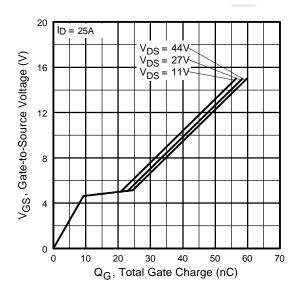


Fig 6. Typical Gate Charge Vs. Gate-to-Source Voltage

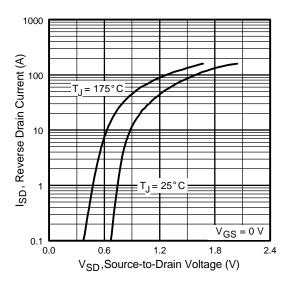


Fig 7. Typical Source-Drain Diode Forward Voltage

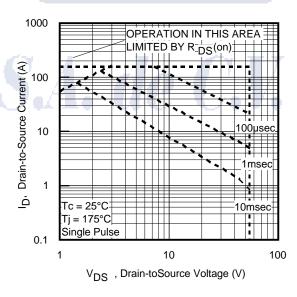


Fig 8. Maximum Safe Operating Area

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4

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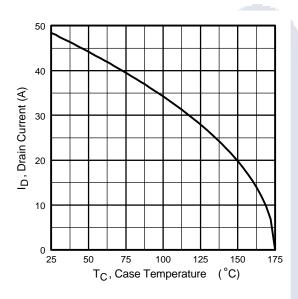


Fig 9. Maximum Drain Current Vs. Case Temperature

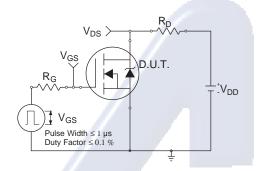


Fig 10a. Switching Time Test Circuit

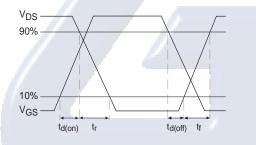


Fig 10b. Switching Time Waveforms

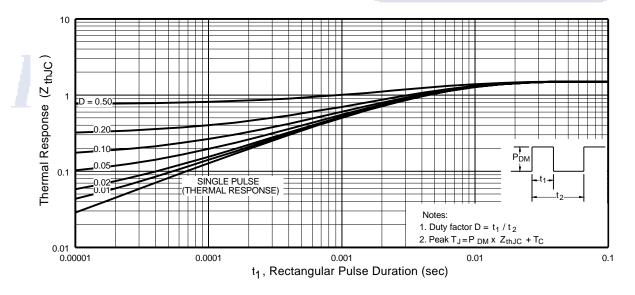


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Case

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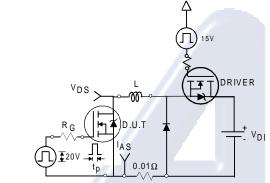


Fig 12a. Unclamped Inductive Test Circuit

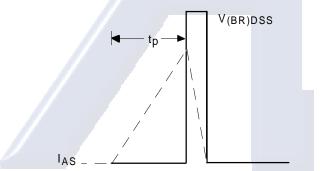


Fig 12b. Unclamped Inductive Waveforms

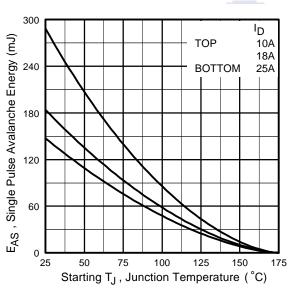


Fig 12c. Maximum Avalanche Energy Vs. Drain Current

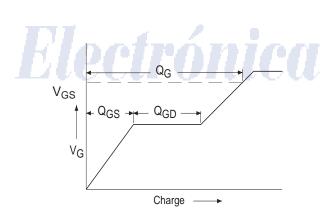


Fig 13a. Basic Gate Charge Waveform

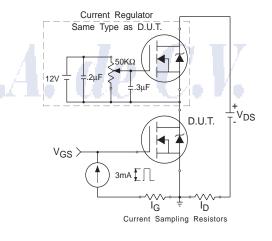


Fig 13b. Gate Charge Test Circuit

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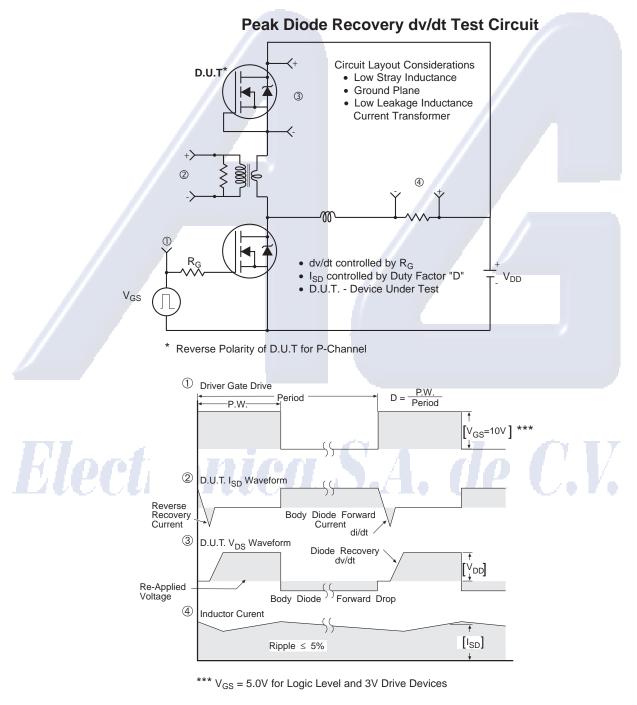
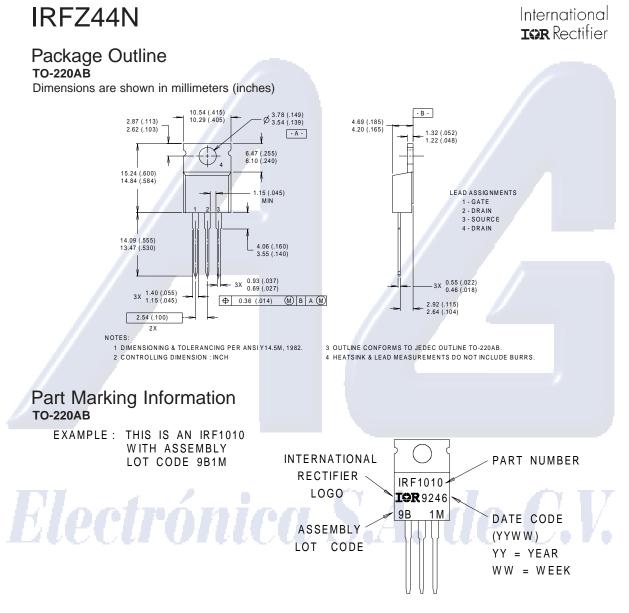


Fig 14. For N-channel HEXFET® power MOSFETs



Data and specifications subject to change without notice. This product has been designed and qualified for the Automotive [Q101] market.

Qualification Standards can be found on IR's Web site.



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8